

Search Notes

Application/Control No.

10/017,174

Examiner

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Applicant(s)/Patent under
Reexamination

DELL ET AL.

Art Unit

2664

SEARCHED

Class	Subclass	Date	Examiner
370	58.2	11/15/2005	BQN
370	422	7/12/2005	BQN
370	380	7/12/2005	BQN
370	388	7/12/2005	BQN
370	427	7/12/2005	BQN
370	366	7/12/2005	BQN
370	367	7/12/2005	BQN
340	2.22	7/12/2005	BQN
340	2.24	7/12/2005	BQN
340	2.26	7/12/2005	BQN
370	54	11/15/2005	BQN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
340	2.22	7/12/2005	BQN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update search EAST (US-GPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM-TDB, and update IDS), see more on search history.	11/15/2005	BQN
Consulted with SPE Wellington Chin	11/15/2005	BQN